



LIGITEK

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BAR DIGIT LED DISPLAY



Lead-Free Parts

LBD336C-XXB

DATA SHEET

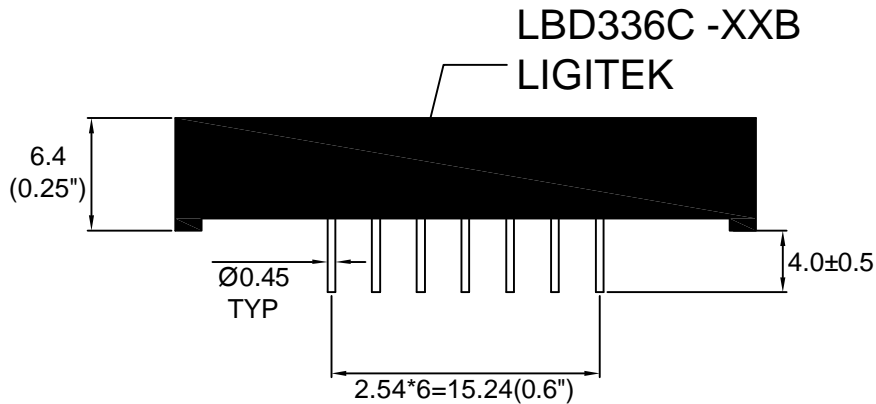
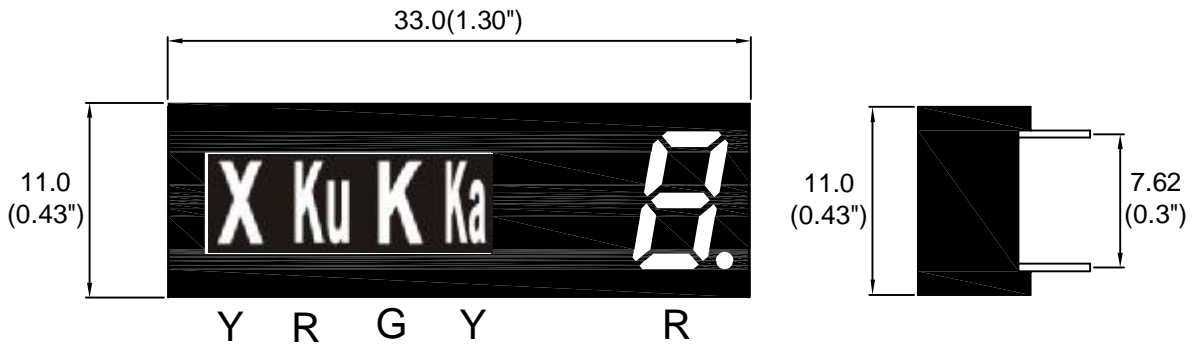
DOC. NO : QW0905-LBD336C-XXB

REV. : A

DATE : 05 - Dec. - 2008



Package Dimensions



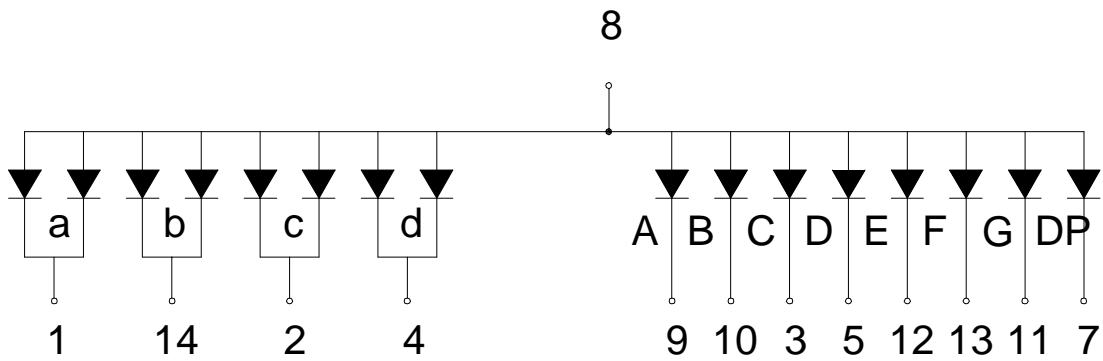
PIN NO. 1 →

- Note : 1.All dimension are in millimeters and (Inch) tolerance is $\pm 0.25\text{mm}(0.01\text{'})$ unless otherwise noted.
 2.Specifications are subject to change without notice.
 3.Film:temperature-resistant $\leq 100^{\circ}\text{C}$.



Internal Circuit Diagram

LBD336C-XXB





Electrical Connection

PIN NO.	LBD336C-XXB
1.	Cathode a
2.	Cathode c
3.	Cathode C
4.	Cathode d
5.	Cathode D
6.	NC
7.	Cathode DP
8.	Common Anode
9.	Cathode A
10.	Cathode B
11.	Cathode G
12.	Cathode E
13.	Cathode F
14.	Cathode b



Absolute Maximum Ratings at Ta=25 °C

Parameter	Symbol	Ratings			UNIT
		Red	Green	Yellow	
Forward Current Per Chip	IF	15	15	15	mA
Peak Forward Current Per Chip (Duty 1/10,0.1ms Pulse Width)	IFP	70	80	50	mA
Power Dissipation Per Chip	PD	50	50	50	mW
Reverse Current Per Any Chip	Ir	10			μA
Operating Temperature	Topr	-25 ~ +85			°C
Storage Temperature	Tstg	-25 ~ +85			°C

Part Selection And Application Information(Ratings at 25°C)

PART NO	CHIP		common cathode or anode	λ P (nm)	Δ λ (nm)	Electrical				IV-M
	Material	Emitted				Vf(v)		Iv(mcd)		
						Min.	Typ.	Min.	Typ.	
LBD336C-XXB	GaAlAs	Red	Common Anode	660	20	1.5	2.1	1.75	3.05	2:1
	GaP	Green		565	30	1.7	2.1	---	---	
	GaAsP/GaP	Yellow		585	35	1.7	2.1	---	---	

Note : 1.The forward voltage data did not including ±0.1V testing tolerance.
2. The luminous intensity data did not including ±15% testing tolerance.

**Test Condition For Each Parameter**

Parameter	Symbol	Unit	Test Condition
Forward Voltage Per Chip	V _f	volt	I _f =10mA
Luminous Intensity Per Chip	I _v	mcd	I _f =10mA
Peak Wavelength	λP	nm	I _f =20mA
Spectral Line Half-Width	$\Delta \lambda$	nm	I _f =20mA
Reverse Current Any Chip	I _r	μA	V _r =5V
Luminous Intensity Matching Ratio	IV-M		



Typical Electro-Optical Characteristics Curve

SR CHIP

Fig.1 Forward current vs. Forward Voltage

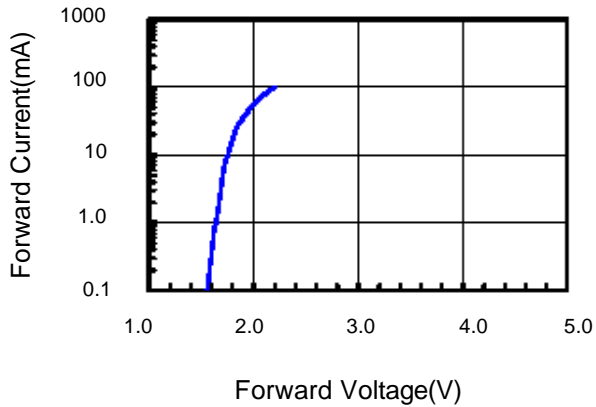


Fig.2 Relative Intensity vs. Forward Current

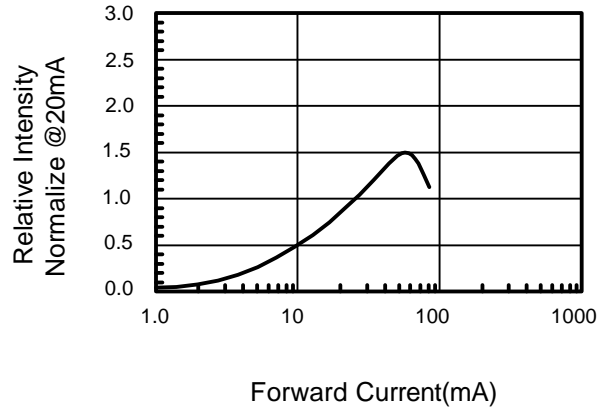


Fig.3 Forward Voltage vs. Temperature

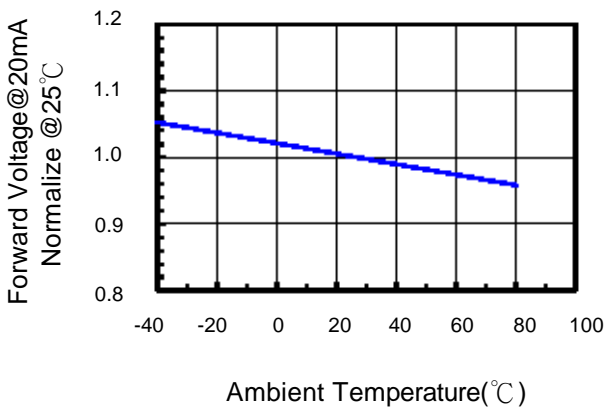


Fig.4 Relative Intensity vs. Temperature

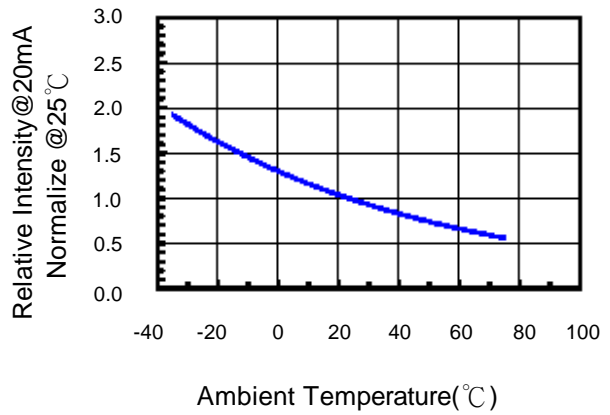
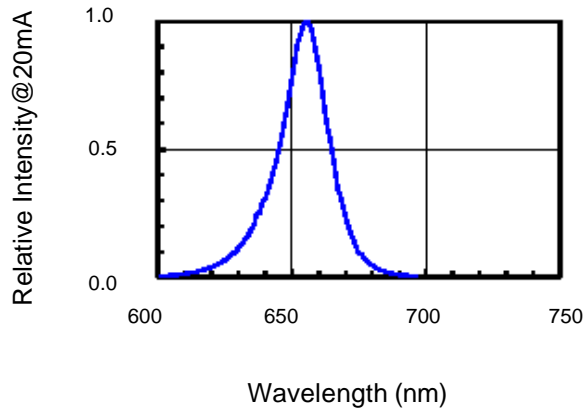


Fig.5 Relative Intensity vs. Wavelength

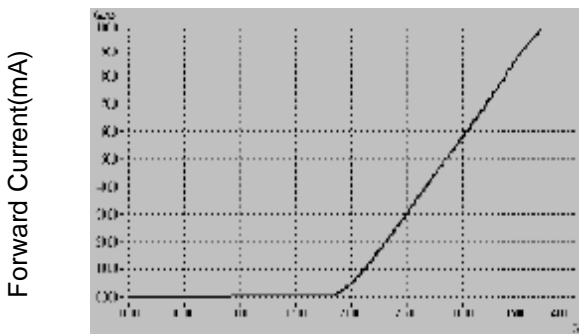




Typical Electro-Optical Characteristics Curve

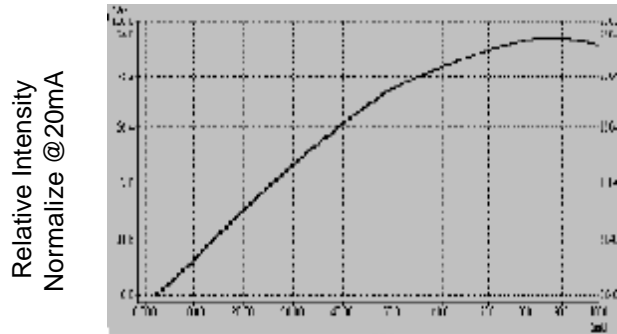
G CHIP

Fig.1 Forward current vs. Forward Voltage



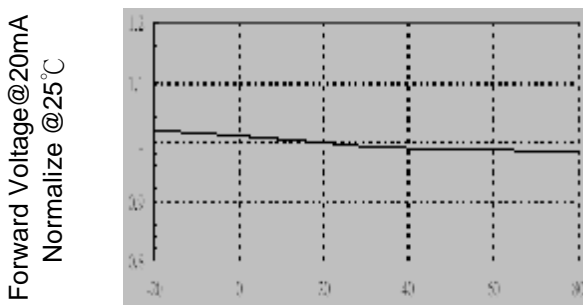
Forward Voltage(V)

Fig.2 Relative Intensity vs. Forward Current



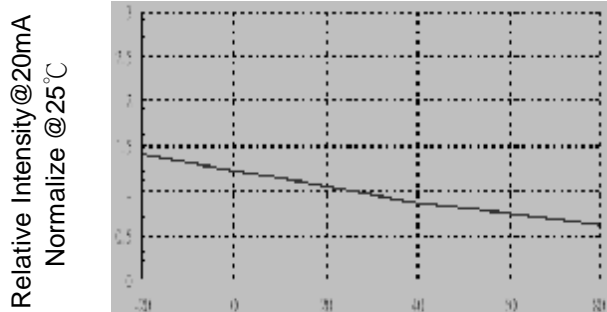
Forward Current(mA)

Fig.3 Forward Voltage vs. Temperature



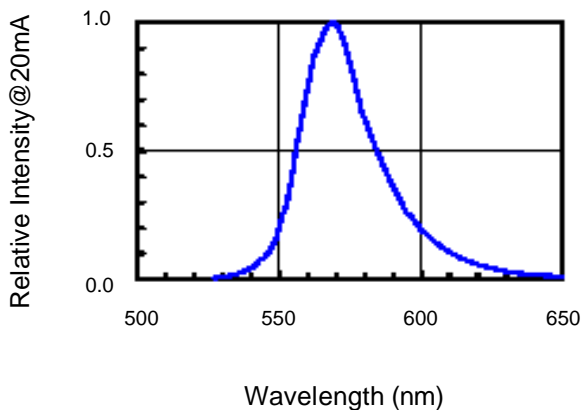
Ambient Temperature(°C)

Fig.4 Relative Intensity vs. Temperature



Ambient Temperature(°C)

Fig.5 Relative Intensity vs. Wavelength





Typical Electro-Optical Characteristics Curve

Y CHIP

Fig.1 Forward current vs. Forward Voltage

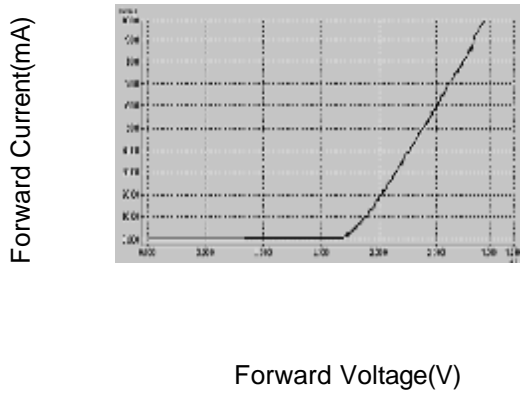


Fig.2 Relative Intensity vs. Forward Current

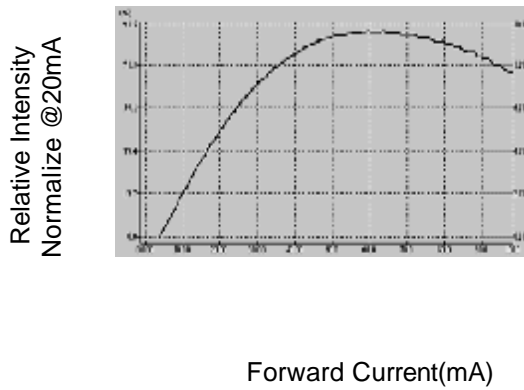


Fig.3 Forward Voltage vs. Temperature

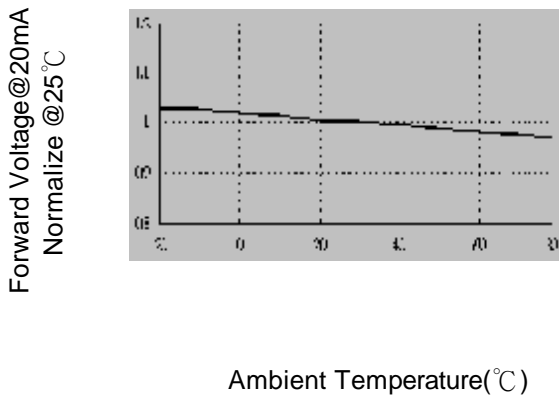


Fig.4 Relative Intensity vs. Temperature

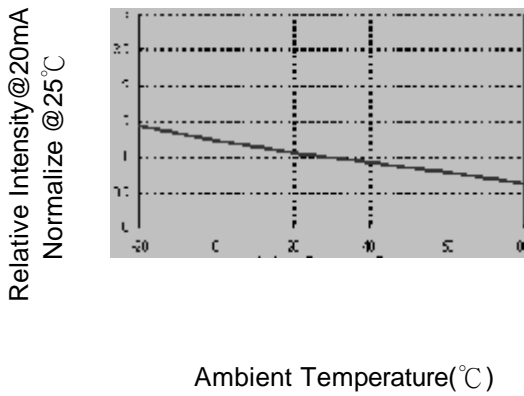
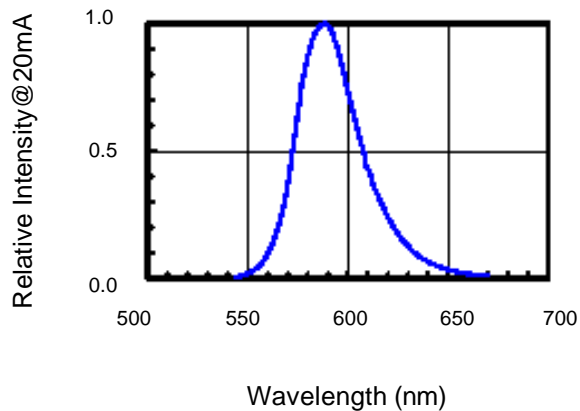


Fig.5 Relative Intensity vs. Wavelength



**Reliability Test:**

Test Item	Test Condition	Description	Reference Standard
Operating Life Test	1.Under Room Temperature 2.If=10mA 3.t=1000 hrs (-24hrs, +72hrs)	This test is conducted for the purpose of determining the resistance of a part in electrical and thermal stressed.	MIL-STD-750: 1026 MIL-STD-883: 1005 JIS C 7021: B-1
High Temperature Storage Test	1.Ta=105°C±5°C 2.t=1000 hrs (-24hrs, +72hrs)	The purpose of this is the resistance of the device which is laid under condition of high temperature for hours.	MIL-STD-883:1008 JIS C 7021: B-10
Low Temperature Storage Test	1.Ta=-40°C±5°C 2.t=1000 hrs (-24hrs, +72hrs)	The purpose of this is the resistance of the device which is laid under condition of low temperature for hours.	JIS C 7021: B-12
High Temperature High Humidity Test	1.Ta=65°C±5°C 2.RH=90%~95% 3.t=240hrs ±2hrs	The purpose of this test is the resistance of the device under tropical for hours.	MIL-STD-202:103B JIS C 7021: B-11
Thermal Shock Test	1.Ta=105°C±5°C & -40°C±5°C (10min) (10min) 2.total 10 cycles	The purpose of this is the resistance of the device to sudden extreme changes in high and low temperature.	MIL-STD-202: 107D MIL-STD-750: 1051 MIL-STD-883: 1011
Solder Resistance Test	1.T.Sol=260°C±5°C 2.Dwell time= 10 ±1sec.	This test intended to determine the thermal characteristic resistance of the device to sudden exposures at extreme changes in temperature when soldering the lead wire.	MIL-STD-202: 210A MIL-STD-750: 2031 JIS C 7021: A-1
Solderability Test	1.T.Sol=230°C±5°C 2.Dwell time=5 ±1sec	This test intended to see soldering well performed or not.	MIL-STD-202: 208D MIL-STD-750: 2026 MIL-STD-883: 2003 JIS C 7021: A-2